

# Device Modeling Report

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PART NUMBER:TLP621\_B  
MANUFACTURER: TOSHIBA



**Bee Technologies Inc.**

## DIODE MODEL

Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## BIPOLAR JUNCTION TRANSISTOR MODEL

Pspice model parameter	Model description
NR	Reverse Emission Coefficient
RB	Base Resistance
RC	Series Collector Resistance
CJE	Zero-bias Emitter-Base Junction Capacitance
CJC	Zero-bias Collector-Base Junction Capacitance
TF	Forward Transit Time
TR	Reverse Transit Time

## VOLTAGE CONTROLLED VOLTAGE SOURCE MODEL(VCVS)

E<Name><(+)Node><(−)Node>VALUE={Expression}

E<Name><(+)Node><(−)Node>TABLE={Expression}

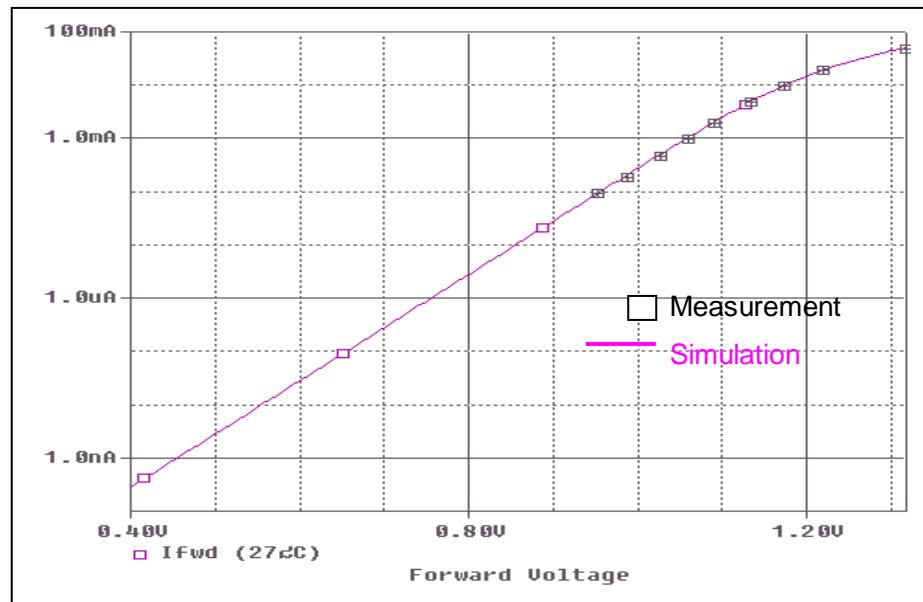
## **VOLTAGE CONTROLLED CURRENT SOURCE MODEL(VCCS)**

E<Name><(+)Node><(−)Node>VALUE={Expression}

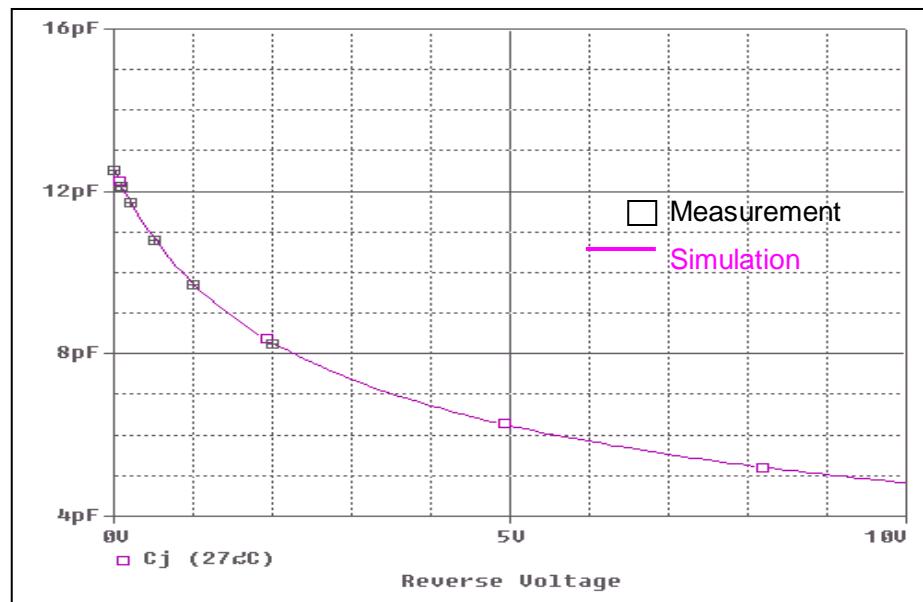
### **CURRENT CONTROLLED MODEL(W)**

Pspice model parameter	Model description
IOFF	Controlling current to Off state
ION	Controlling current to On state
ROFF	Off Resistance
RON	On Resistance

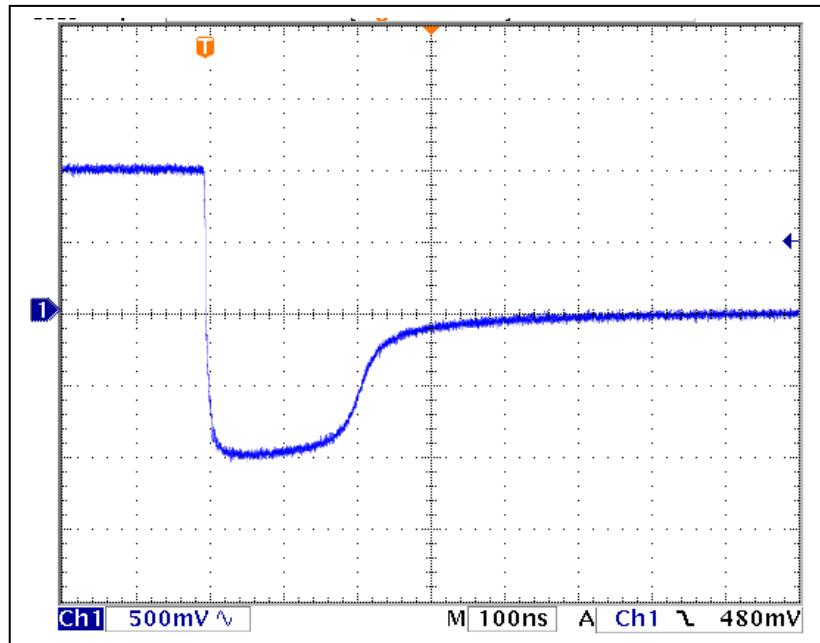
## Input Device Forward Current Characteristics



## Input Device Junction Capacitance Characteristics



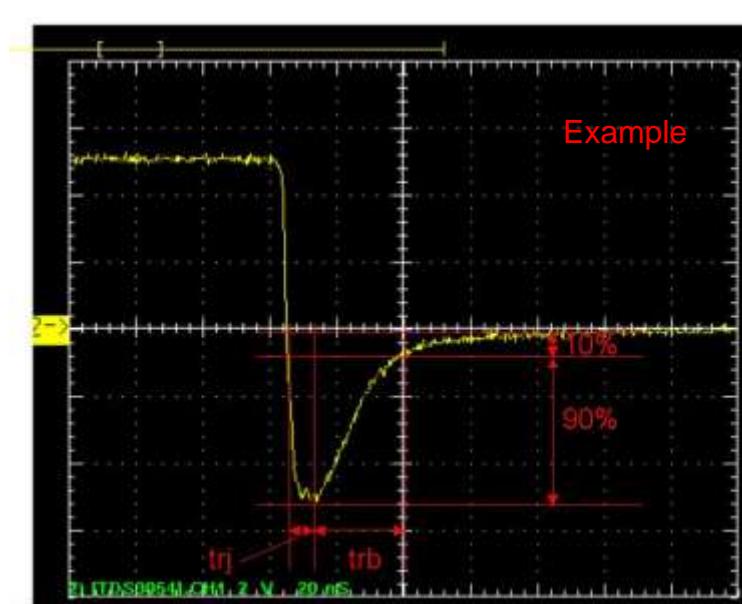
## Input Device Reverse Recovery Characteristics



trj=146n(s)

trb=158n(s)

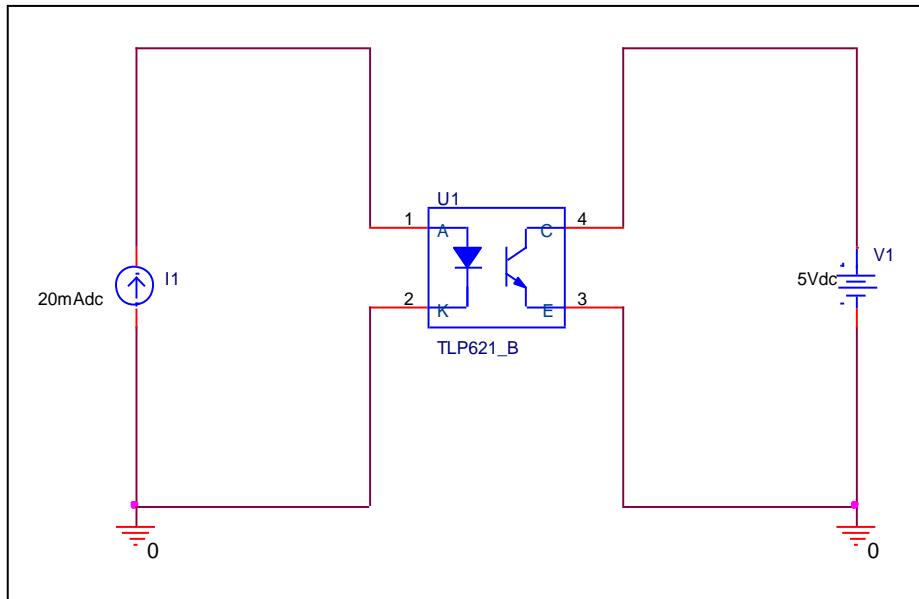
Conditions: Ifwd=Irev=0.04(A), RI=50



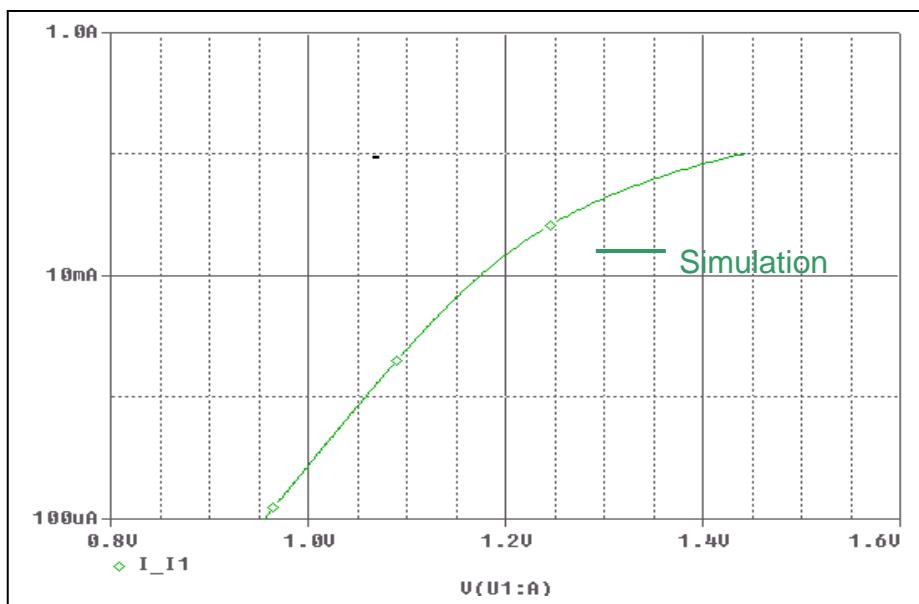
Relation between trj and trb

## LED IV Curve Characteristics

Evaluation Circuit



Simulation result

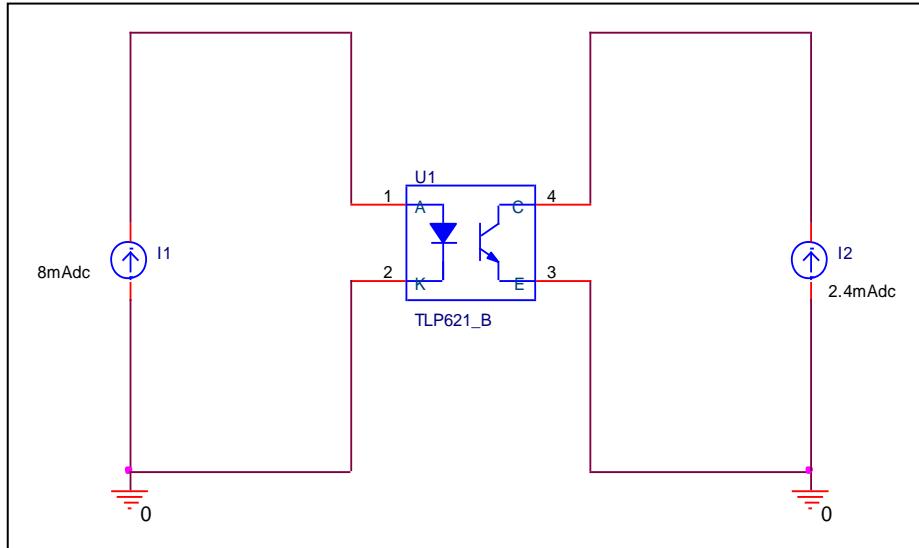


## **Comparison Table**

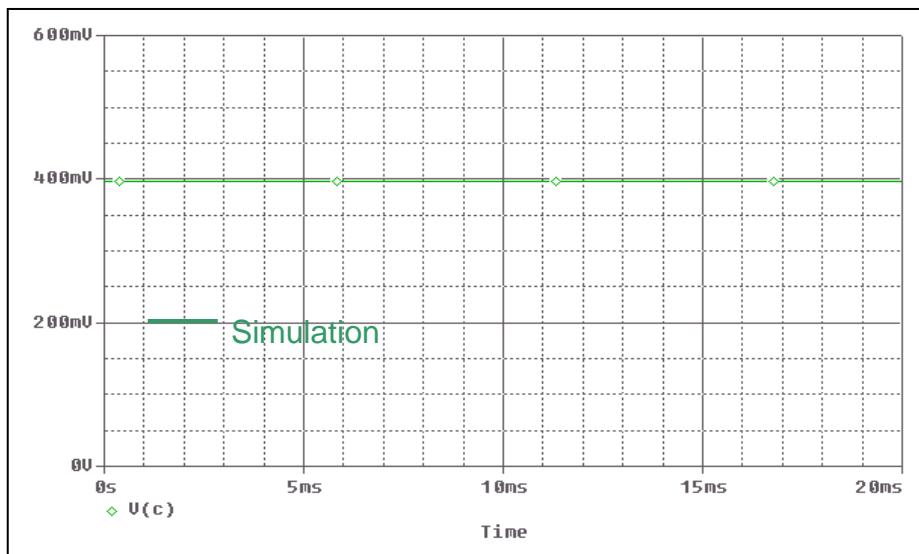
Ifwd(A)	Vfwd(V)		% Error
	Measurement	Simulation	
0.0001	0.952	0.955	0.315
0.0002	0.988	0.9861	-0.192
0.0005	1.028	1.0265	-0.146
0.001	1.06	1.0576	-0.226
0.002	1.09	1.0894	-0.055
0.005	1.134	1.1349	0.079
0.01	1.174	1.1741	0.009
0.02	1.220	1.2225	0.205
0.05	1.318	1.3172	-0.061

## Transistor Saturation Characteristics

Evaluation Circuit



Simulation result

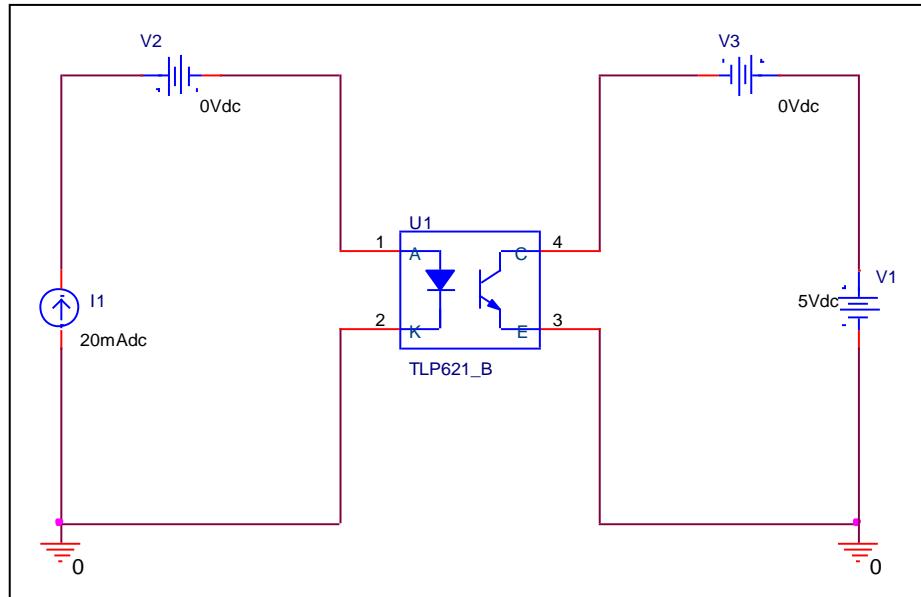


Comparison Table

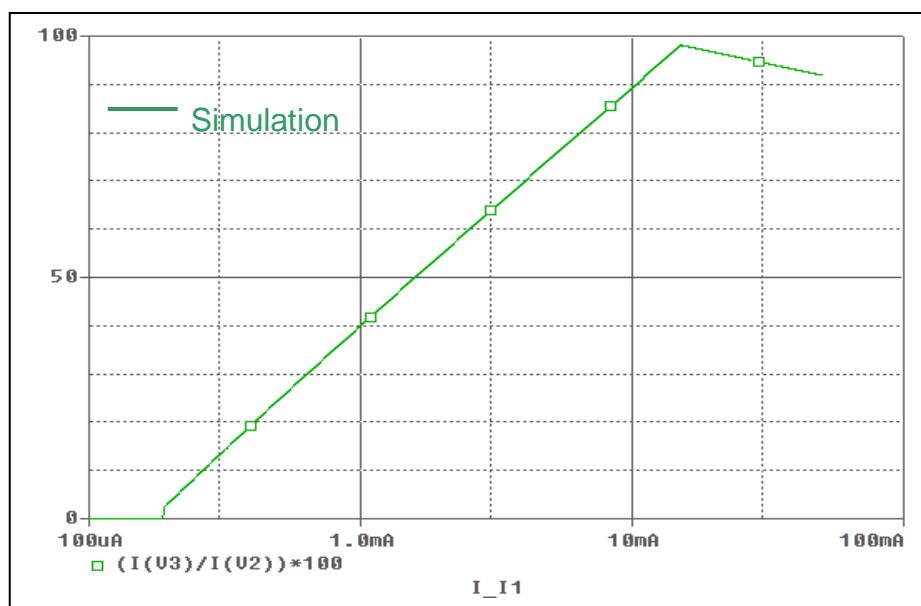
	Measurement	Simulation	% Error
V <sub>ce(sat)</sub> (V)	0.4	0.398	-0.5

## CTR(Current Transfer Ratio) Characteristics

Evaluation Circuit



Simulation result



## Rise Curve Table

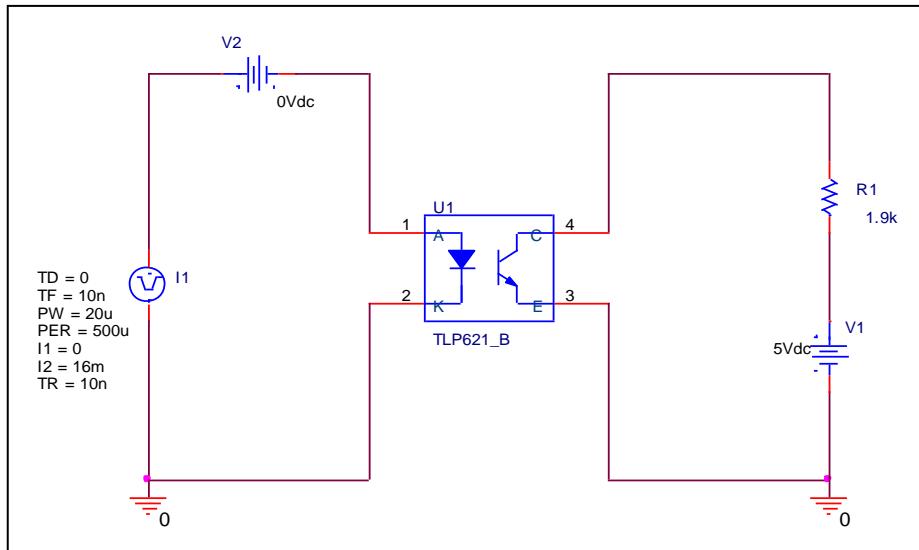
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
0.5	25	24.666	-1.336
0.8	34	35.084	3.188
1	39	39.972	2.492
2	55	54.989	-0.020
5	75	74.601	-0.532
8	85	84.595	-0.476
10	90	89.326	-0.749
15	98	98.191	0.195

## Fall Curve Table

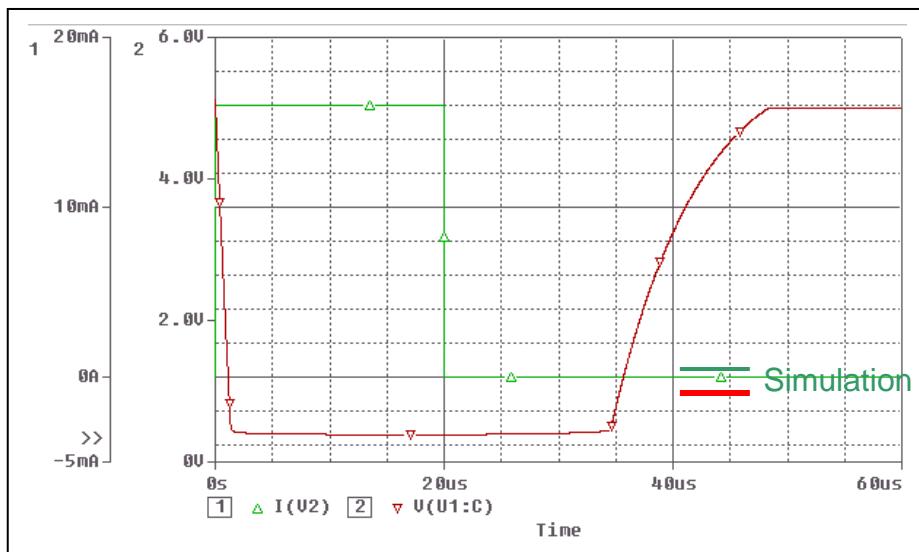
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
15	98	98.191	0.195
20	97	96.687	-0.323
30	95	94.552	-0.472
40	93	93.026	0.028
50	92	91.834	-0.180

## Switching Time Characteristics

Evaluation Circuit



Simulation result



Comparison Table

Vcc=5V, IC=16mA, RL=1.9kΩ	Measurement	Simulation	% Error
Ts (us)	15	15.063	0.42
Tf (us)	25	25.073	0.292